

INTERFERENCE

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L17	1	((test\$4 near10 (IC or (integrated adj circuit))) and ((partition\$4 or divid\$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack\$5 and conduct\$3 and I/O and pad).CLM.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:48

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	7918	(test\$4 same (IC or (integrated adj circuit))) and pattern and chip and pack\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:58
L2	2862	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L3	9	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and "716"/\$.ccs.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:57
L4	116	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L5	74	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L6	3	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct\$4 and partition\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L7	64	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L8	64	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct\$4 and function\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50

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L9	20	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and (I/O or input/output) and conduct\$4 and function\$3 and (partition\$3 or divid\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L10	96	(test\$4 same (IC or (integrated adj circuit)) same pattern) and chip and pack\$5 and pad and (fan-out or fan adj2 out) and ("716"/\$.ccls. or "324"/\$.ccls. or "257"/\$.ccls.)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 20:50
L11	820	(test\$4 near10 (IC or (integrated adj circuit))) and ((partition\$4 or divid\$3) same (IC or (integrated adj circuit))) and pattern and chip and pack\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:12
L12	268	(test\$4 near10 (IC or (integrated adj circuit))) and ((partition\$4 or divid\$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:13
L13	9	(test\$4 near10 (IC or (integrated adj circuit))) and ((partition\$4 or divid\$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack\$5 and (fan-out or fan adj out) and (I/O or (input same output) same pad)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:18
L14	14	(test\$4 near10 (IC or (integrated adj circuit))) and ((partition\$4 or divid\$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack\$5 and (fan-out or fan adj out)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:19
L15	63	(test\$4 near10 (IC or (integrated adj circuit))) and ((partition\$4 or divid\$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack\$5 and conduct\$3 and (I/O same pad)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:20
L16	1	(test\$4 near10 (IC or (integrated adj circuit))) and ((partition\$4 or divid\$3) same (IC or (integrated adj circuit))) and pattern and pitch and chip and pack\$5 and conduct\$3 and (I/O same pad) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 21:47


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» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

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- ☐ 1. **Description and evaluation of the FAST-Net smart pixel-based optical inter prototype**
 Haney, M.W.; Christensen, M.P.; Milojkovic, P.; Fokken, G.J.; Vickberg, M.; Gil J.; Ekman, J.; Chandramani, P.; Kiamilev, F.;
[Proceedings of the IEEE](#)
 Volume 88, Issue 6, June 2000 Page(s):819 - 828
 Digital Object Identifier 10.1109/5.867695
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(1096 KB) IEEE JNL
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- ☐ 2. **A process-independent, 800-MB/s, DRAM byte-wide interface featuring cc interleaving and concurrent memory operation**
 Griffin, M.M.; Zerbe, J.; Tsang, G.; Ching, M.; Portmann, C.L.;
[Solid-State Circuits, IEEE Journal of](#)
 Volume 33, Issue 11, Nov. 1998 Page(s):1741 - 1751
 Digital Object Identifier 10.1109/4.726569
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(344 KB) IEEE JNL
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| #2 | test <and> ic <and> partition <and> packaging <and> pad <and> pitch <and> I/O |
| #3 | test <and> ic <and> partition <and> packaging <and> pad <and> pitch <and> pattern <and> I/O |
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